OIPE	Forr
DEC 0 5 20	
A PARTY PARTY	

orm PTO-1449 U.S. DEPARTMENT OF COMMERCE quivalent | PATENT AND TRADEMARK OFFICE

**ATTY. DKT. NO.** 500.43701X00

**SERIAL NO.** 10/809,464

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

OKUDA et al

**APPLICANT** 

FILING DATE March 26, 2004 **GROUP** 2621

### **U.S. PATENT DOCUMENTS**

Ex. In	itial	Doc. No.	Date	Name	Class	Subclass	Filing Date
/E.P./	AA	5,699,447	12/97	Alumot et al			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						

#### **U.S. PATENT APPLICATIONS**

	Publication Number	Name	Publication Date
Al			
AJ			
AK			
AL			

#### **FOREIGN PATENT DOCUMENTS**

	Doc. No.	Date	Country	Country Class	Subclass	Translation/Abstract?		
						Yes	No	
AM		·						
AN								
AO					,			
AP								
AQ								

### **OTHER DOCUMENTS**

<b>-</b>		Data Canaldared
	AT	
	AS	
	AR .	

Examiner Date Considered

/Edward Park/ 07/07/2007

MAR 2 2 2006 W

Form PTO-1449 THE BEPARTMENT OF COMMERC		<b>SERIAL NO.</b> 10/809,464			
Equivalent PATENT AND TRADEMARK OFFIC	E 500.43701X00				
	APPL	APPLICANT			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT	OKU	DA et al			
	FILING DAT	E GROUP			
(Use several sheets if necessary)	March 26, 20	04 2621			

## **U.S. PATENT DOCUMENTS**

Ex. Initial	Doc. No.	Date	Name	Class	Subclass	Filing Date
AA						- · · · · · · · · · · · · · · · · · · ·
AB						
AC						
AD						
AE						
AF						
AG						
AH						

### **U.S. PATENT APPLICATIONS**

	Publication Number	Name	Publication Date
Al			
LA	,		
AK			
AL			

# **FOREIGN PATENT DOCUMENTS**

	Doc. No.	oc. No. Date Country	Country	Class	Subclass	Translation/Abstract?		
·					Yes	No		
AM								
AN								
AO								
AP								
AQ								

## OTHER DOCUMENTS

pp 418-435  Henry, et al "Application of ADC Techniques to Characterize Yield-Limiting Defects With the Overlay of E-Test/Inspecting Data On Short Loop Process Testers" Advances Semiconductor Manufacturing Conference, 1999 IEEE/SEMI Boston, MA 8-10 Sept 330-337					
/E.P./	AS	Xu, L, "Methods of Combining Multiple Classifiers And Th Recognition" IEEE Transactions on Systems, Man and C pp 418-435			
/E.P./	AR	Kuk Wo Ko, Such Cho, "Solder Joints Inspection Using A Based Classification Method", IEEE Transactions On Electrol. 23, no. 2, April 2000 pp 93-103			

APR 2 1 2006 Viction Act of 1995

PTO/SB/08A (08-03) Approved for use through 07/31/2006. OMB 0651-0031 U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Re ersons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449A/PTO

Sheet

#### INFORMATION DISCLOSURE STATEMENT BY APPLICANT

C	omplete if Known
Application Number	10/809,464
Filing Date	3/26/2004
First Named Inventor	OKUDA et al
Art Unit	2621
Examiner Name	
Attorney Docket Number	500.43701X00

Examiner	Cite	Document Number		ATENT D		ame of Patentee or		ages, Columns, Lines, Where	
Initials'	No.1		MM-DE			ant of Cited Document		elevant Passages or Relevant	
		Number-Kind Code <sup>2</sup> (# known)						Figures Appear	
/E.P./		US- 6,922,482	7/20	8/05		Ben-Porath			
		US-							
		US-							
		US-							
		US-							
		US-							
		US-							
		US-							
-		US-							
		US-							
		US-							
		US-							
		US-							
		US-							
		US-							
		US-							
		US-				•			-
		US-							
			FOREIC	N PATENI	. 000	LIMENTS			
				PALEN		VIIIENIO	<u> </u>	Pages Calumna Lines	Г
Examiner Initials'	Cite No.1	Foreign Patent Docu-		Publication MM-DD-Y				Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	1
/E.P./		JP 2001-1356		5/18/0		Applied Materials, Ir		English Translation	Γ
				0,.0/(	•				$\vdash$

FOREIGN PATENT DOCUMENTS						
Examiner Initials'	Cite No.	Foreign Patent Document  Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>6</sup> (ff known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	76
/E.P./		JP 2001-135692	5/18/01	Applied Materials, Inc.	English Translation	<u> </u>
					· · · · · · · · · · · · · · · · · · ·	<u> </u>
			ļ			<del> </del>

Examiner	/Edward Park/	Date	07/07/2007
Signature	/Edward Land	Considered	

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional). 2 See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. 3 Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 5 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. 6 Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application: Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number

					Horniedon Bricos II Contanto a Valla Cirio Contagnitatinoci	
Substitute for form 1449A/PTO				Complete if Known		
				Application Number	Not Yet Assigned	
INFORMATION DISCLOSURE				Filing Date	March 26, 2004	
	STATEMENT BY APPLICANT			First Named Inventor	Hirohito OKUDA	
	•		•	Art Unit		
	(use as many sheets as ne	cessa	nv)(vr)	Examiner Name		
Sheet	1	of	1	Attomey Docket Number	500.43701X00	

U.S. PATENT DOCUMENTS						
Examiner Initials'	Cite No.1	Document Number  Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
		US				
		US-				
		US-				
		US-				
		US-	1			
		US-	]			
		US-				
		US-				
		US-				
		US-				
		US-				
		US-				
		US-				
		us-				
		บร-				
		US-				

FOREIGN PATENT DOCUMENTS						
Initials' N	Cite	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
	No. <sup>1</sup>	Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)				T <sup>©</sup>
/E.P./		JP A-2001-135692	May 18, 2001	A. BEN-PORETH		X
			<del>-</del>			<del> </del>
-			-		•	₩
						<u> </u>
			·			<u> </u>

Examiner	/Edward Park/	Date	07/07/2007
Signature	1 - 4 1 4 1 4 1 4 1 4 1 4 1 4 1 4 1 4 1	Considered	0110112001

Burden Hour Statement: This form is estimated to take 2.0 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Assistant Commissioner for Patents, Washington, DC 20231.

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at <a href="https://www.uspto.gox">www.uspto.gox</a> or MPEP 901.04. ³Enter Office that issued the document, by the two-letter code (WIPO Standard St.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁴Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁴Applicant is to place a check mark here if English language Translation is attached.